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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT					ATTY, DOCKET NO. ASMEX 376A	APPLICA 10/623	ATION NO. ,482	
					APPLICANT Todd et al.			
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	 CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
RP	1	5,389,570	2/14/95	Shi	ozawa			
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	BEAPPLICANT	APPLICANT Todd et al.	
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BY APPLICANT TRADEMINI	APPLICANT Todd et al.	
(USE SEVERAL SHEETS IF NECESSARY)	FILING DATE July 18, 2003	GROUP 2812

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10/623482 Application No. INFORMATION DISCLOSURE Filing Date July 18, 2003 First Named Inventor Michael A. Todd et al. STATEMENT BY APPLICANT Art Unit 2812 (Multiple sheets used when necessary) Examiner Unknown Attorney Docket No. ASMEX.376A SHEET 1 OF 1

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	NON PATENT LITERATURE DOCUMENTS								
Examiner Initials Cite No. Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.									
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Examiner Signature for Portfley Date Considered 6-8-05

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICATION NO. 10/823,482
INFORMATION DISCLOSURE STATEMENT BY APPLICANT PE	APPLICANT Todd et al.	
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ŔĎ	11.	5,607,724	3/4/97	Beinglass et al.						
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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY, DOCKET NO. ASMEX.376A

APPLICATION NO. 10/623,482

INFORMATION DISCLOSURE STATEMENT

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APPLICANT Todd et al.

FILING DATE July 18, 2003

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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	FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASMEX.376A	APPLICATION NO. Unknown	
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RP	2	5,916,365	6/29/99	Sherman			
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RP	4	6,159,828	12/12/00	Ping et al.			
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